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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	Lamon		
09/328,391	06/09/1999		ATTORNEY DOCKET NO.	CONFIRMATION NO.	
	00.03,1333	VINCENT BERGER	0154-2811-2	6762	
OBLON, SPIN	ON DAVIS HIGHWAY	, MAIER & NEUSTADT	EXAMI	NER	
	ARLINGTON, VA 22202 BROCK		BROCK II,	II, PAUL E	
			ART UNIT	PAPER NUMBER	
			2815	6762 MINER II, PAUL E	

DATE MAILED: 02/21/2003

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)	- fw
Office Action Summary		09/328,391	BERGER ET AL.	
		Examiner	Art Unit	
		Paul E Brock II	2815	
Period fo	Th MAILING DATE of this communication app		1	ss
A SH THE I - Exter after - If the - If NO - Failu - Any I	ORTENED STATUTORY PERIOD FOR REPLY MAILING DATE OF THIS COMMUNICATION. nsions of time may be available under the provisions of 37 CFR 1.13 SIX (6) MONTHS from the mailing date of this communication. period for reply specified above is less than thirty (30) days, a reply period for reply is specified above, the maximum statutory period we te to reply within the set or extended period for reply will, by statute, eply received by the Office later than three months after the mailing and patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be till within the statutory minimum of thirty (30) day fill apply and will expire SIX (6) MONTHS from Cause the application to become ARANDONE	mely filed ys will be considered timely. I the mailing date of this commu	nication.
1)⊠	Responsive to communication(s) filed on 10 F	ebruary 2003 .		
2a)⊠		s action is non-final.		
3)	Since this application is in condition for allowa		rosecution as to the m	erits is
Dispositi	closed in accordance with the practice under <i>l</i> on of Claims	Ex parte Quayle, 1935 C.D. 11, 4	453 O.G. 213.	
4)🖂	Claim(s) 1-24 is/are pending in the application.			
	4a) Of the above claim(s) <u>4,5,7-10,16,17 and 19</u>	9-22 is/are withdrawn from consi	deration.	•
5)	Claim(s) is/are allowed.			
6)⊠	Claim(s) <u>1-3,6,11-15,18,23 and 24</u> is/are rejected	ed.		
7)	Claim(s) is/are objected to.			
8)[Claim(s) are subject to restriction and/or	election requirement.		
Applicati	on Papers			
9) 🔲 🗆	The specification is objected to by the Examiner			
10)⊠ 1	he drawing(s) filed on $\underline{20 \ June \ 2002}$ is/are: a)	$\centerise{3}$ accepted or b) $\centerise{1}$ objected to by t	he Examiner.	
	Applicant may not request that any objection to the	· · · · · · · · · · · · · · · · · · ·	• •	
11)[]	he proposed drawing correction filed on	is: a) ☐ approved b) ☐ disappro	oved by the Examiner.	
	If approved, corrected drawings are required in repl			
	he oath or declaration is objected to by the Exa	miner.		
Priority u	nder 35 U.S.C. §§ 119 and 120			
13)	Acknowledgment is made of a claim for foreign	priority under 35 U.S.C. § 119(a)-(d) or (f).	
a)[All b) Some * c) None of:			
	1. Certified copies of the priority documents	have been received.		
:	2. Certified copies of the priority documents	have been received in Application	on No	
	3. Copies of the certified copies of the priorit application from the International Bure se the attached detailed Office action for a list o	eau (PCT Rule 17.2(a)).	·	е
	cknowledgment is made of a claim for domestic	·		lication).
a)	☐ The translation of the foreign language proveknowledgment is made of a claim for domestic	isional application has been rec	eived.	
Attachment(, , , , , , , , , , , , , , , , , , , ,		
2) 🔲 Notice	of References Cited (PTO-892) of Draftsperson's Patent Drawing Review (PTO-948) ation Disclosure Statement(s) (PTO-1449) Paper No(s)	5) Notice of Informal P	(PTO-413) Paper No(s) Patent Application (PTO-152	<u> </u>
6. Patent and Tra TO-326 (Rev.		on Summary	Part of Paper	No. 28

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DETAILED ACTION

Election/Restrictions

1. Claims 4, 5, 7 – 10, 16, 17 and 19 – 22 withdrawn from further consideration pursuant to 37 CFR 1.142(b), as being drawn to a nonelected invention, there being no allowable generic or linking claim. Applicant timely traversed the restriction (election) requirement in Paper No. 11.

Drawings

2. The corrected or substitute drawings were received on June 20, 2002. These drawings are accepted.

Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. Claims 1, 2, 3, 11, 13, 14, 15 and 23 are rejected under 35 U.S.C. 103(a) as being unpatentable over Rosencher et al. (USPAT 5086327, Rosencher) in view of Katoh (USPAT 5041882).

With regard to claim 1, Rosencher discloses in figure 3 an electromagnetic wave detector.

Rosencher discloses in figure 3 a stack of layers made of III-V semiconductor materials.

Rosencher discloses in figure 3 a conduction band profile of the materials defining at least one quantum well (3), the quantum well having at least one first discrete energy level populated with

electrons that are capable of passing to a second energy level under absorption of an electro magnetic wave. Rosencher discloses in figure 3 means for counting the electrons in the second energy level. Rosencher discloses in figure 3 wherein the stack of layers of semiconductor materials furthermore comprises a transfer barrier layer (4), and an electron storage layer (5) separated from the quantum well by the transfer barrier layer. Rosencher discloses in figure 4 wherein a thickness of the transfer barrier layer is at least one order of magnitude greater than a thickness of the quantum well. Rosencher discloses in figure 3 wherein a lowest energy level of a conduction band of the transfer barrier layer being greater than the lower energy levels of the quantum well and the electron storage layers. Rosencher does not disclose that the conduction band profile of the stack of layers of semiconductor materials decreases from the quantum well to the electron storage layer. Katoh teaches in column 3, lines 37 - 48 a lower energy level of a conduction band profile of a stack of layers of semiconductor materials decreases from a quantum well to a electron storage layer so as to further a flow of electrons from the second energy level to the electron storage layer. It would have been obvious to one of ordinary skill in the art at the time of the present invention to use the transfer barrier layer with a decreasing lower energy level of its conduction band of Katoh in the method of Rosencher in order to establish an electron accelerating electric field within the barrier layer as stated by Katoh in column 3, lines 37 - 48.

With regard to claim 2, Rosencher discloses in figure 3 wherein the stack of layers made of III-V semiconductor materials furthermore comprises a first barrier layer (2) and a third barrier layer (6), both of the first and third layers being made of semiconductor materials such

that a lowest energy level of a conduction band of the both layers is respectively greater than a lowest energy level of the conduction band of the quantum well and of the electron storage layer.

With regard to claim 3, Katoh discloses in column 3, lines 37 – 48 wherein a decreasing profile of the lowest energy level of the conduction band of the transfer barrier layer is obtained with a semiconductor alloy having a composition varying from the quantum well to the electron storage layer.

With regard to claim 11, Rosencher teaches in the abstract the electromagnetic wave detector further comprising means for resetting the flow of the electrons in the storage layer.

With regard to claim 13, Rosencher discloses in figure 3 an electromagnetic wave detector. Rosencher discloses in figure 3 a stack of layers made of III-V semiconductor materials. Rosencher discloses in figure 3 a conduction band profile of the materials defining at least one quantum well (3), the quantum well having at least one first discrete energy level populated with electrons that are capable of passing to a second energy level under absorption of an electro magnetic wave. Rosencher discloses in figure 3 a counting unit configured to count the electrons in the second energy level. Rosencher discloses in figure 3 wherein the stack of layers of semiconductor materials furthermore comprises a transfer barrier layer (4), and an electron storage layer (5) separated from the quantum well by the transfer barrier layer. Rosencher discloses in figure 4 wherein a thickness of the transfer barrier layer is at least one order of magnitude greater than a thickness of the quantum well. Rosencher discloses in figure 3 wherein a lowest energy level of a conduction band of the transfer barrier layer being greater than the lower energy levels of the quantum well and the electron storage layers. Rosencher does not disclose that the conduction band profile of the stack of layers of semiconductor

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materials decreases from the quantum well to the electron storage layer. Katoh teaches in column 3, lines 37 – 48 a lower energy level of a conduction band profile of a stack of layers of semiconductor materials decreases from a quantum well to a electron storage layer so as to further a flow of electrons from the second energy level to the electron storage layer. It would have been obvious to one of ordinary skill in the art at the time of the present invention to use the transfer barrier layer with a decreasing lower energy level of its conduction band of Katoh in the method of Rosencher in order to establish an electron accelerating electric field within the barrier layer as stated by Katoh in column 3, lines 37 - 48.

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With regard to claim 14, Rosencher discloses in figure 3 wherein the stack of layers made of III-V semiconductor materials furthermore comprises a first barrier layer (2) and a third barrier layer (6), both of the first and third layers being made of semiconductor materials such that a lowest energy level of a conduction band of the both layers is respectively greater than a lowest energy level of the conduction band of the quantum well and of the electron storage layer.

With regard to claim 15, Katoh discloses in column 3, lines 37 – 48 wherein a decreasing profile of the lowest energy level of the conduction band of the transfer barrier layer is obtained with a semiconductor alloy having a composition varying from the quantum well to the electron storage layer.

With regard to claim 23, Rosencher teaches in the abstract the electromagnetic wave detector further comprising means for resetting the flow of the electrons in the storage layer.

5. Claims 6, 12, 18 and 24 are rejected under 35 U.S.C. 103(a) as being unpatentable over Rosencher and Katoh as applied to claim 1 above, and further in view of Nanbu (JPPAT 361054673).

With regard to claims 6 and 18, Rosencher and Katoh do not teach that first and second ohmic contacts are located at the electron storage layer. Nanbu discloses in the Constitution section and figure 1 a first (4) and second (5) ohmic contacts, both of the first and second ohmic contacts being located at an electron storage layer (10) so as to carry out a measurement of photocurrent in a plane of the storage layer. It would have been obvious to one of ordinary skill in the art at the time of the present invention to use the ohmic contacts of Nanbu in the device of Rosencher and Katoh in order to stably realize electron mobility as stated by Nanbu in the abstract portion of the English translation.

With regard to claims 12 and 24, Nanbu discloses in figure 1 that the third and fourth contacts are located on either side of a stack of layers of semiconductor materials.

Response to Arguments

- 6. Applicant's arguments filed January 7, 2003 have been fully considered but they are not persuasive.
- 7. With regard to the applicant's arguments that "the definition of " 'one order of magnitude,' as shown for example in <u>Fowler et al</u>, *Concise Oxford Dictionary of Current English*, 9th Ed., Clarendon Press, Oxford, p. 960 (1990), is a power of 10... and consequently 200 A is not about one order of magnitude greater than 80 A," it should be noted that the power

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of ten of any particular number N, can be written in the form of n x 10^y (N = n x 10^y), wherein y is the power of ten of N and n is the number N written with only one number greater than zero to the left of the decimal point. For example N = 125 can be written where n = 1.25 and y=2, or $125=1.25\times10^2$. Therefore, 200 can be written as 2.0×10^2 , and 80 can be written as 8.0×10^1 . It can be seen that 2 is greater than 1 by one (2-1=1). Thus, the order of magnitude of 200 is greater than the order of magnitude of 80 by one, a power of ten. Similarly, it can be shown that $20 (2.0 \times 10^1)$ is one order of magnitude greater than 5 $(5.0 \times 10^0) (1-0=1)$. Therefore, the applicant's arguments are not persuasive, and the rejection is proper.

8. With regard to the Applicant's arguments that "a quantity about one order of magnitude greater than 80A is about 800 A, and consequently 200 A is not about one order of magnitude greater than 80 A," while 800 is one order of magnitude greater than 80, 800 is ten times the value of 80. The multiplicity of 800 with regard to 80 is ten (800 is ten times 80). It can also be seen that 200 is an order of magnitude greater than 80, but not ten times 80. Therefore, while the applicant confuses multiplicity with order of magnitude, it should now be clear that they are not the same thing. Rosencher clearly reads on the claim limitation of "a thickness of the transfer barrier layer is at least one order of magnitude greater than a thickness of the quantum well." Therefore, the applicant's arguments are not persuasive, and the rejection is proper.

Conclusion

9. **THIS ACTION IS MADE FINAL.** Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Paul E Brock II whose telephone number is (703)308-6236. The examiner can normally be reached on 8:30 AM-5:30 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Eddie Lee can be reached on (703)308-1690. The fax phone numbers for the organization where this application or proceeding is assigned are (703)308-7722 for regular communications and (703)308-7722 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703)308-0956.

Ba

Paul E Brock II February 14, 2003

SUPERVISORY PATENT EXAMINER

TECHNOLOGY CENTER 2800